DOCKET NO: 263261US0PCT

## IN THE UNITED STATES PATENT & TRADEMARK OFFICE

IN RE APPLICATION OF

:

HITOSHI KATO, ET AL.

: EXAMINER: TO BE ASSIGNED

SERIAL NO: 10/518,025

:

FILED: DECEMBER 15, 2004

: GROUP ART UNIT: TO BE ASSIGNED

FOR: CVD METHOD FOR FORMING SILICON NITRIDE FILM ON TARGET

**SUBSTRATE** 

## PRELIMINARY AMENDMENT

COMMISSIONER FOR PATENTS ALEXANDRIA, VIRGINIA 22313

SIR:

Prior to examination on the merits, please amend the above-identified application as follows:

Amendments to the Specification begin on page 2 of this paper.

Remarks/Arguments begin on page 3 of this paper.